

Development of readout ASIC for FPCCD vertex detector

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FPCCD vertex detector

■ Pixel occupancy $< \sim 1\%$

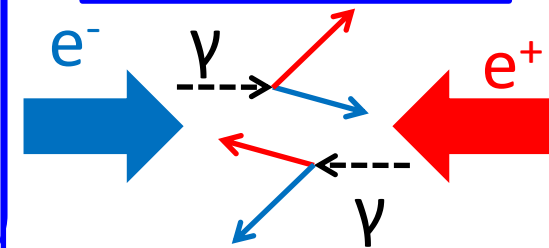
- Large pixel occupancy in the Inner most layer due to pair background events.

➤ Fine Pixel

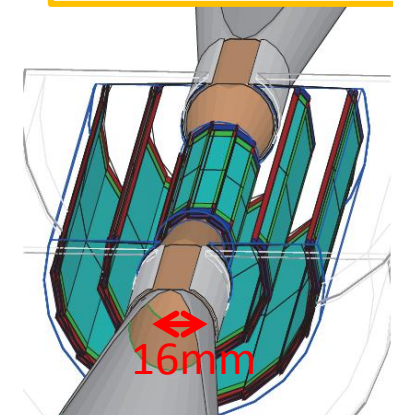
■ Fine Pixel CCD(FPCCD)

- geometry: 3 double layers
 - Pixel size: $5 \times 5 \text{ } \mu\text{m}^2$
 - Sensitive region: 15 μm (full depleted)
- 20,000 \times 128 pix/ch
- total #ch \sim 6,000ch
- **Total $\sim 10^{10}$ pixels**

Pair background



Vertex detector



Thickness 50 μm FPCCD sensor



FPCCD vertex detector

Pixel occupancy $< \sim 1\%$

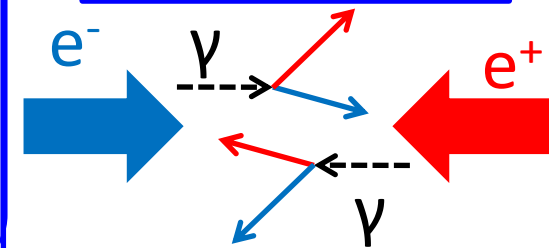
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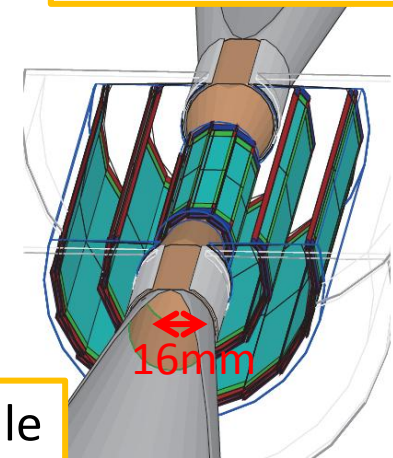
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Vertex detector



Sensor module

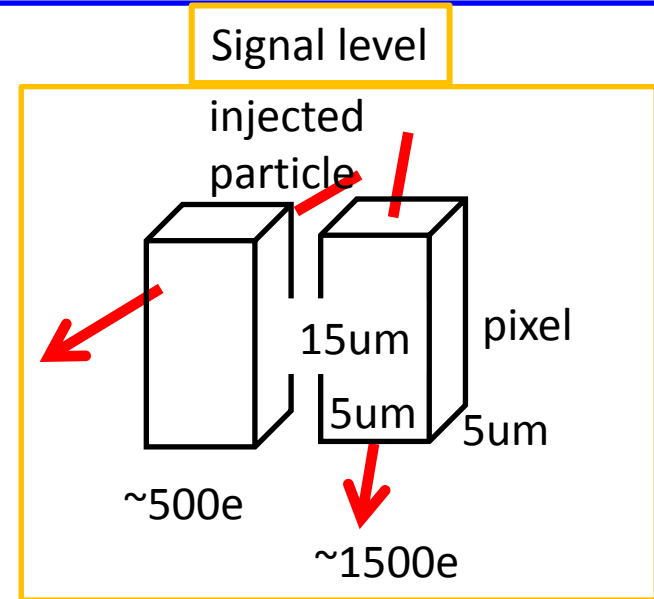
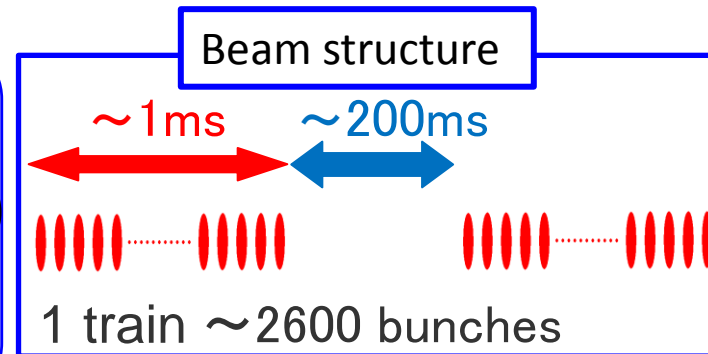


Requirements to readout system

- Readout speed $> 10\text{Mpix/sec}$
 - Readout in inter-train time (200ms)
 - $20,000 \times 128\text{pix}/200\text{ms}$

- Noise level $< 30e^-$
 - Small signal : $\sim 500e^-$

- Power consumption $< 6\text{mW/ch}$
 - Placed in -50°C cryostat
 - Total power consumption $< 100\text{W}$



➤ Develop readout system that meets these requirements

Prototype of readout ASIC

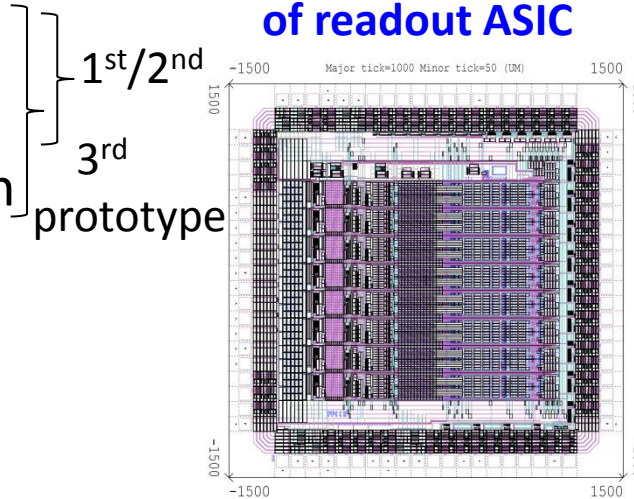
Aim of prototype

- readout speed > 10 Mpix/sec
- Noise level < 30e-
- Power consumption < 6 mW/ch

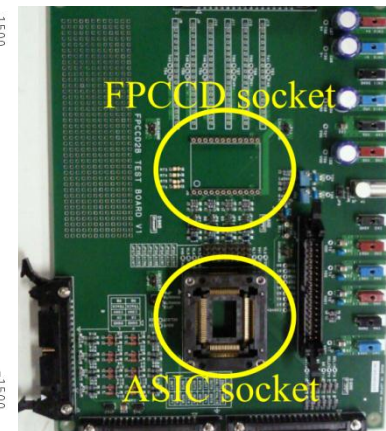
2nd prototype of readout ASIC

- 0.35 μm TSMC process
- # of channels : 8 ch
- Chip size : 4.3 mm × 4.3 mm
- 8 bit signal (100 MHz CK)

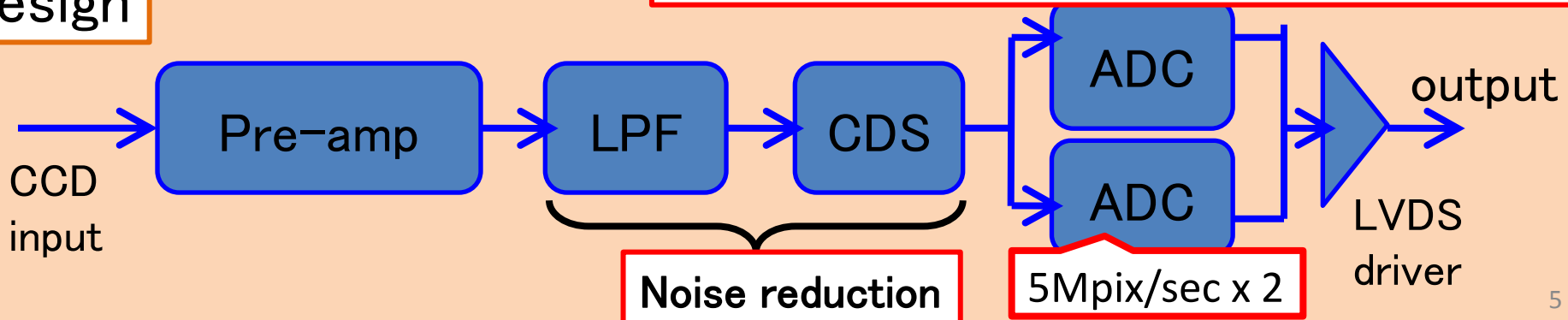
Layout 2nd prototype of readout ASIC



Test board 2nd prototype ASIC



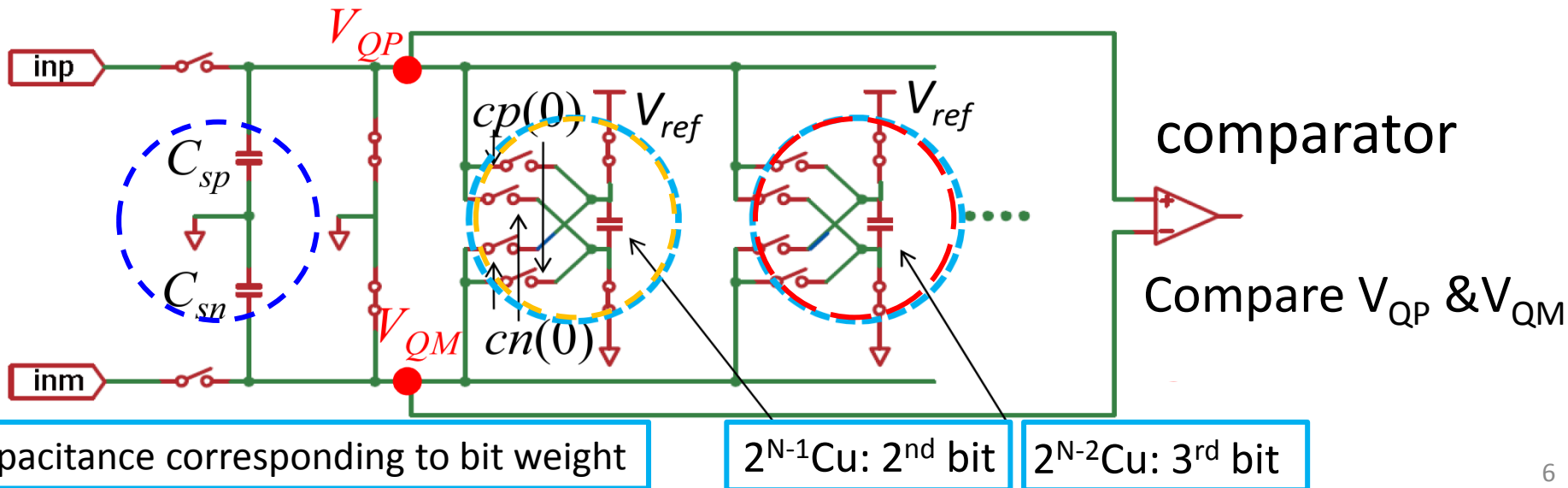
Charge sharing ADC
(low power consumption & relatively high speed)



Charge sharing ADC

mechanism

1. store signal at C_{SP} and C_{SN} and compare V_{QP} and V_{QM} .
→ determine most significant bit (MSB)
2. switch on either cp or cn , depending on result 1.
→ compare V_{QP} and V_{QM} → determine second bit
3. ... and so on..



Problems of 1st prototype

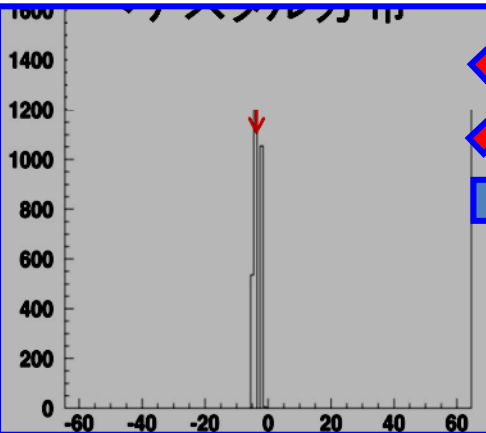
■ Limitation of Readout speed (1.5Mpix/sec)

- Possibility of current shortage to ADC comparator.

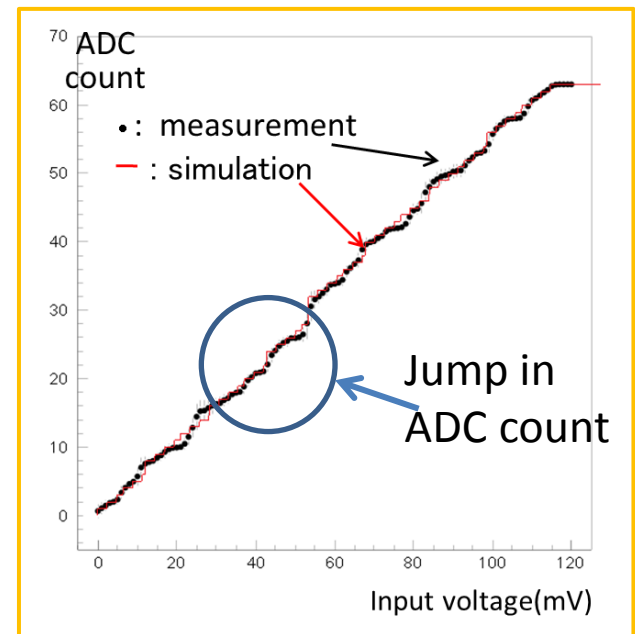
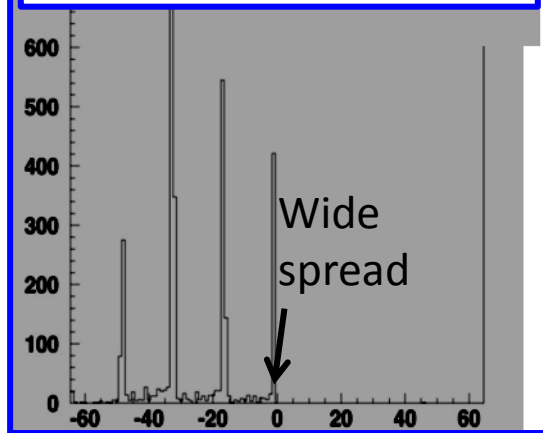
■ Large jumps in ADC output

- As an effect of stray capacitance, there is a possibility that capacitor ratio isn't corresponding to bit weight.

1.5Mpix/sec ADC output
Pedestal distribution

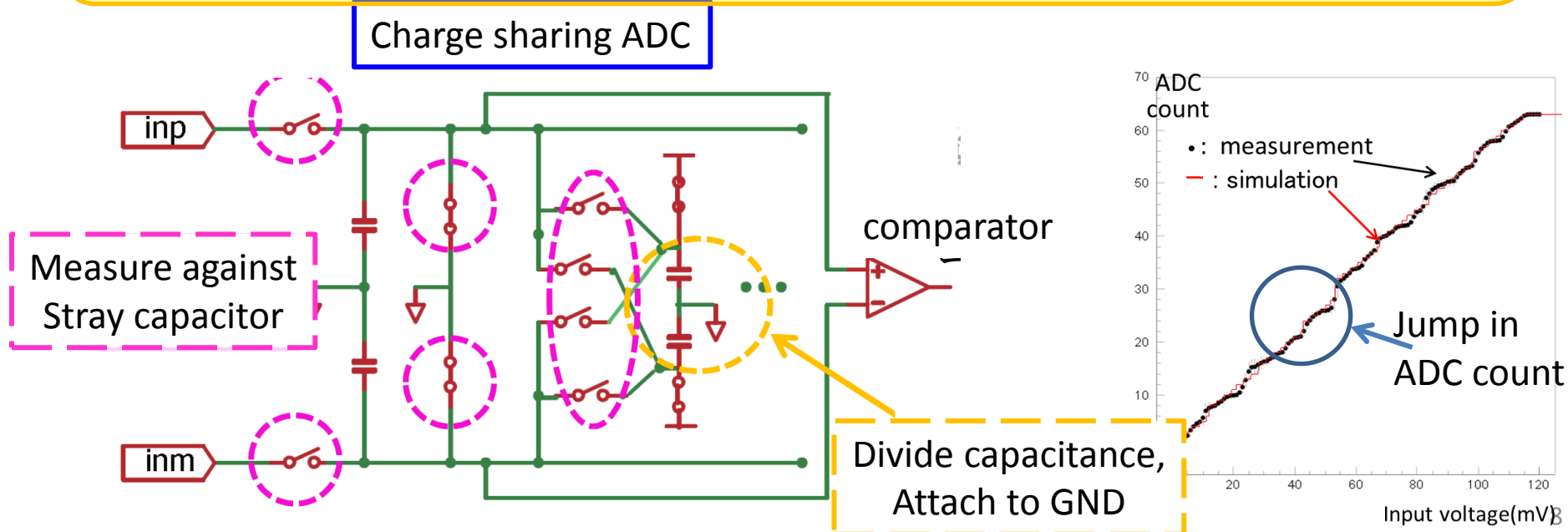


5Mpix/sec ADC output
Pedestal distribution



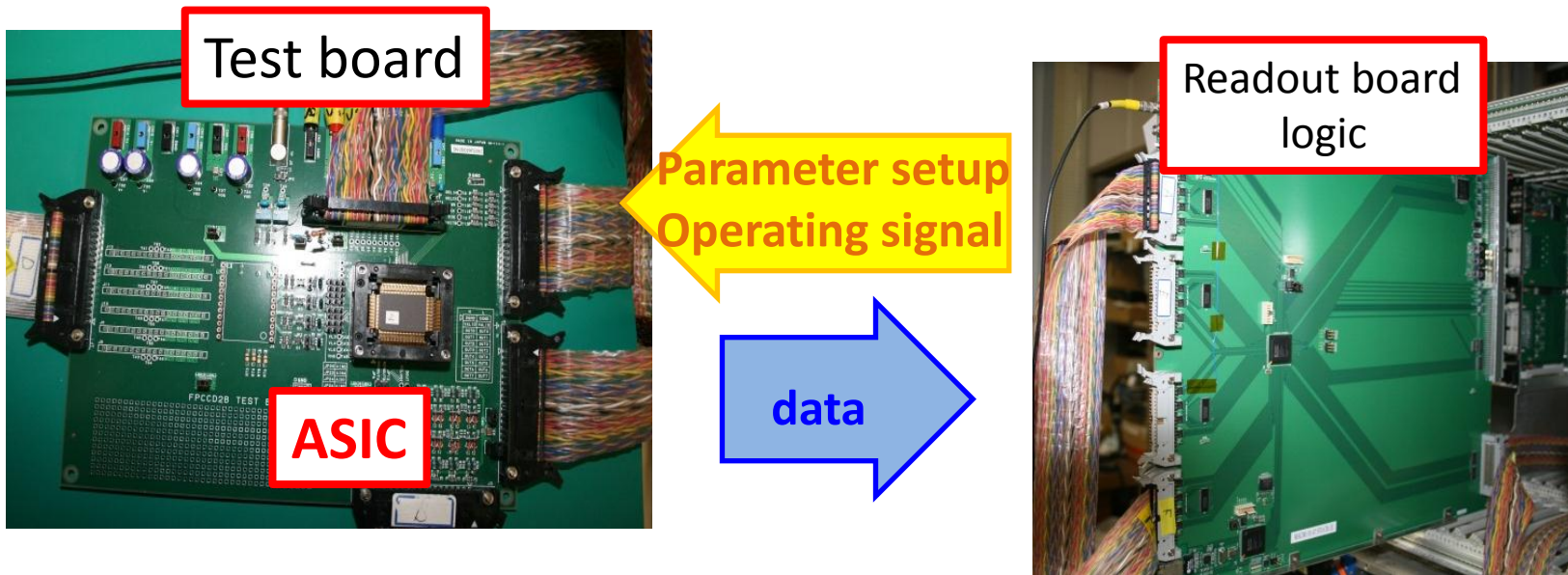
Changes in 2nd prototype

- Countermeasure against readout speed limitation:
 - Increase current supply to ADC comparator by increasing # of pins 80→100
- Countermeasure against jumps in ADC count:
 - Suppress the effect of stray capacitance attached to switches and in between GND.



Setup for 2nd prototype testing

- Implement logic circuit in FPGA.
- Data transfer via VME bus.
- SiTCP usable as well.

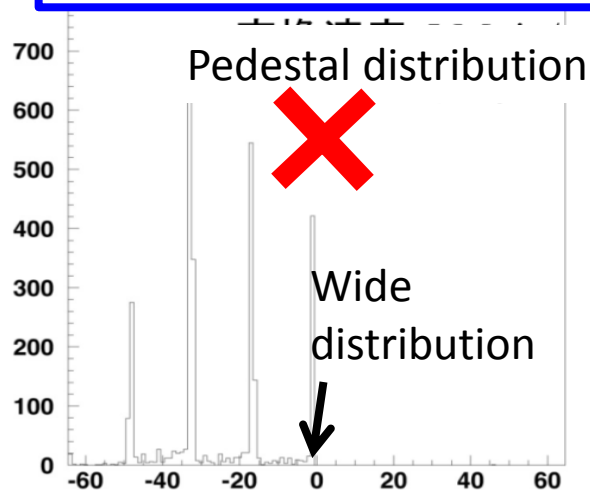


Readout speed of 2nd prototype

■ Verified 10Mpix/sec(100MHz CK) operation

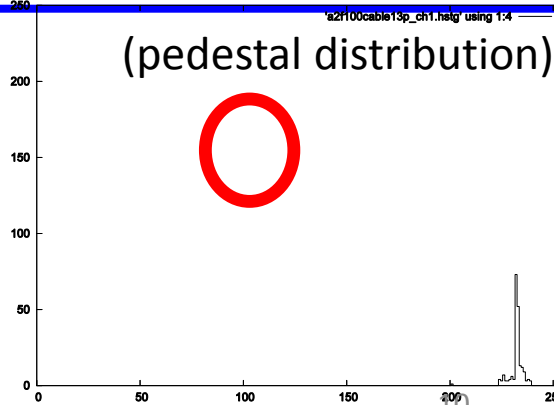
- Currently evaluating of linearity
(Residual distribution)

1st prototype 5Mpix/sec

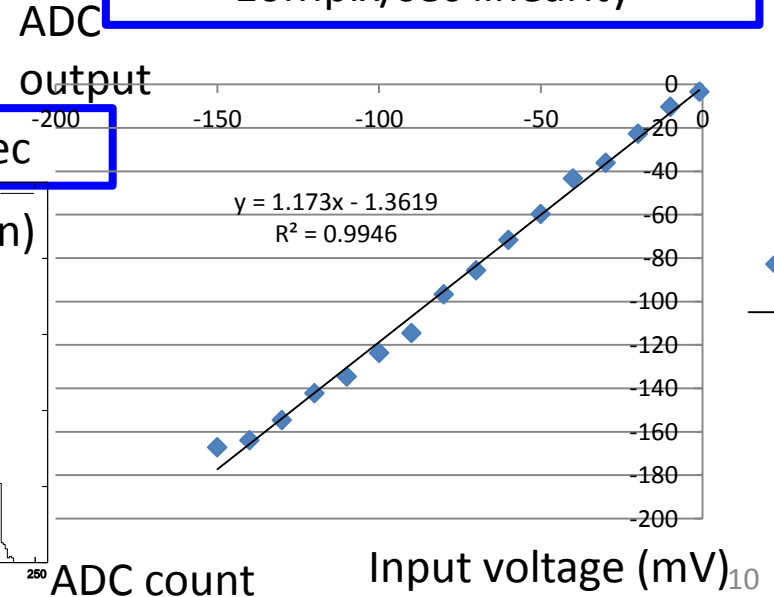


2nd prototype 10Mpix/sec

(pedestal distribution)



2nd prototype
10Mpix/sec linearity



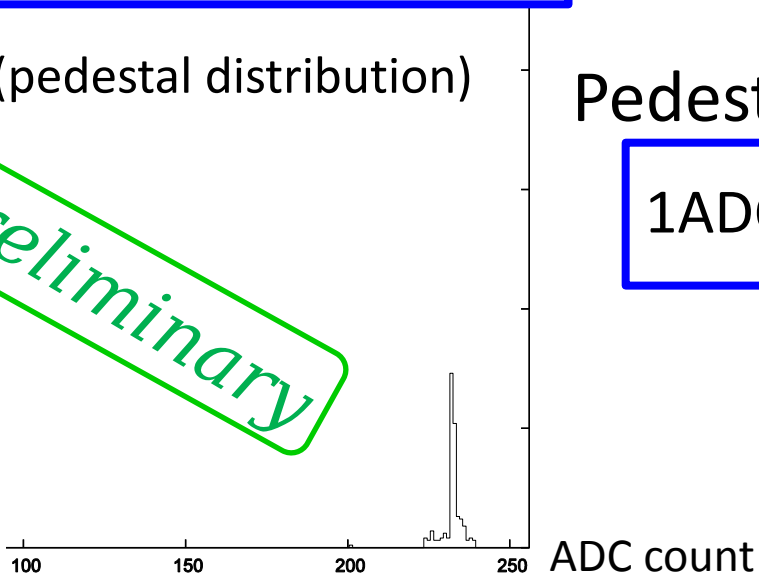
noise level of 2nd prototype

- Required noise level < 30e⁻
 - Measured noise level ~ **41e⁻**
 - currently evaluating noise features (Gain, LPF dependence etc..)

2nd prototype 10Mpix/sec

(pedestal distribution)

preliminary

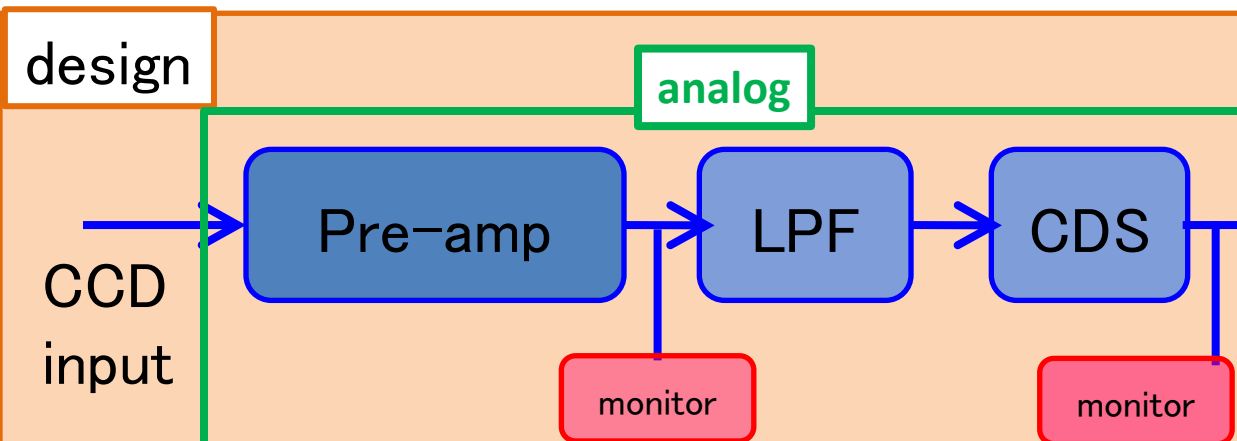


Pedestal to noise (electron) conversion

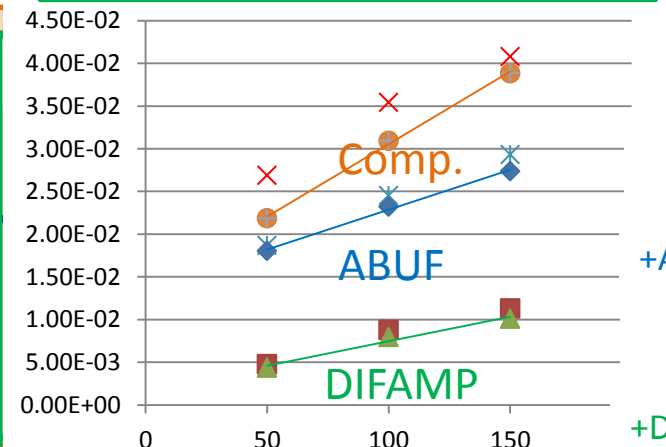
$$1\text{ADC} \sim \text{gradient} \times \frac{1(\text{pF})}{20(\text{pF})} \times \frac{1(e^-)}{5(\mu\text{V})} \text{ electron}$$

Power consumption counter measurements

- Required power consumption < 6mW/ch
 - Measured power consumption 30.8mW/ch ($\hat{=}$ simulation)
 - Digital analog power consumption in compatible order.
 - Drastic changes needed. Process: 0.35 μ m \rightarrow 0.25 μ m (or 0.18 μ m)
- changes in next prototype (analog)
 - enable to turn monitor circuit (analog buffer) off
 - Substitute LPF, CDS with low power consuming ABUF

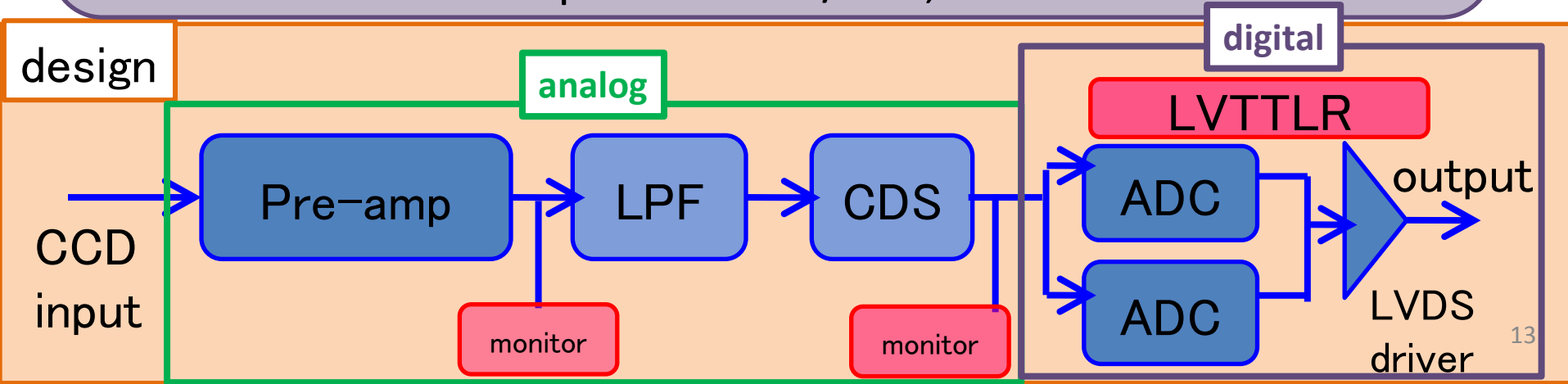


Analog current consumption



Power consumption counter measurements

- Required power consumption < 6mW/ch
 - Measured power consumption 30.8mW/ch ($\hat{=}$ simulation)
 - Digital analog power consumption in compatible order.
 - Drastic changes needed. Process: 0.35 μ m \rightarrow 0.25 μ m (or 0.18 μ m)
- changes in next prototype (digital)
 - Change so there is no DC current in LVTTLR (receiver for parameter setting signal).
 - current consumption: 1.3mA/cell, maximum 22mA



summary

2nd prototype was developed to meet readout speed and noise level

■ Readout speed

- **Succeeded in operating under 10Mpix/sec readout speed , which was difficult in 1st prototype.**

■ Noise level : 41e- (preliminary)

■ Power consumption

- Measured power consumption 30.8mW/ch
- Through simulation , methods to achieve low power consumption are under review.

	Requirement	measurement
Readout speed	10Mpix/sec	10Mpix/sec
noise	30e-	41e-
Power consumption	6mW/ch	30.8mW/ch